QUALIFICATION PLAN

PCN #: JAON-21DZUH494

Date:
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Qualification of palladium coated copper with gold flash (CuPdAu) bond wire and G700LS molding compound in selected products of the 150K and 160K wafer technologies available in 28L SSOP package at ANAP assembly site.

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Purpose: Qualification of palladium coated copper with gold flash (CuPdAu) bond wire and G700LS molding compound in selected products of the 150K and 160K wafer technologies available in 28L SSOP package at ANAP assembly site.

MP code: DE021TN2X024

Part No.: PIC16F57T-I/SS024

BD No: BDM-000835B

CCB No.: 1708

Package:

Type 28L SSOP

Width or Size 0.209"

Die thickness: 15

Die size: 60.5x53.9

MSL: 1

Lead frame:

Paddle size: 154x200

Material C194

Surface Ring Ag

Treatment Rough

Process etched

Leadlock yes

Part Number 101383340

Strip OMLF

Wire:

Material CuPdAu

Die Attach Epoxy:

Part Number 8290

Conductive Yes

Mold Compound:

Part Number G700LS

Lead finish: matte tin

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Standard Pb-free Solderability	JESD22B-102E; Perform 8 hour steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.	22	5	1	27	> 95% lead coverage	5	Standard Pb-free solderability is the requirement. SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes.
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	3	24	0 fails after TC	5	30 bonds from a minimum of 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	3	24	0	5	30 bonds from a minimum of 5 devices.
Wire Sweep		5	0	3	15	0		Required for any reduction in wire bond thickness.
Physical Dimensions	Measure per JESD22 B100 and B108	10	0	3	30	0	5	
External Visual	Mil. Std. 883-2009/2010	All devices prior to submission for qualification testing	0	3	ALL	0	5	
HTSL (High Temp Storage Life)	+175 C for 504 hours or 150°C for 1008 hrs. Electrical test pre and post stress at +25°C and hot temp.85oC, (1 lot to be tested at 125°C)	45	5	1	50	0	10	Must be in progress at time of package release to production, but completion is not required for release to production.
Preconditioning - Required for surface mount devices	+150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020D for package type; Electrical test pre and post stress at +25°C. MSL1 @ 260°C	231	15	3	738	0	15	Spares should be properly identified. 77 parts from each lot to be used for HAST, Autoclave, Temp Cycle test.
HAST	+130°C/85% RH for 96/192 hours. Electrical test pre and post stress at +25°C and hot temp. (1 lot to be tested at 125°C)	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Unbiased HAST	+130°C/85% RH for 96/192 hrs. Electrical test pre and post stress at +25°C	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	-65°C to +150°C for 500/1000 cycles. Electrical test pre and post stress at hot temp; 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress. (1 lot to be tested at 125°C)	77	5	3	246	0	15	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.